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| <b>Search Notes</b><br> | <b>Application/Control No.</b><br>10614542 | <b>Applicant(s)/Patent Under Reexamination</b><br>CHEN, SHIWEN |
|  | <b>Examiner</b><br>Widhalm, Angela         | <b>Art Unit</b><br>2152  |

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|-----------------|-----------------|-------------|-----------------|
| <b>SEARCHED</b> |                 |             |                 |
| <b>Class</b>    | <b>Subclass</b> | <b>Date</b> | <b>Examiner</b> |
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| <b>SEARCH NOTES</b>   |             |                 |
| <b>Search Notes</b>   | <b>Date</b> | <b>Examiner</b> |
| Consult comments presented by previous examiner and applicant; Review previously used prior art | 07/10/2006  | AMW             |
| Consult with B.Jaroenchonwanit, T.Swann   | 07/11/2006  | AMW             |
| Telephone Interview with Applicant  | 07/12/2006  | AMW             |
| Update EAST search  | 08/04/2006  | AMW             |
| Update EAST Search  | 3/6/2007    | AMW             |
| Consult with V.Lesniewski   | 3/13/2007   | AMW             |
| Consult with K.Lin, V.Lesniewski  | 3/15/2007   | AMW             |

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| <b>INTERFERENCE SEARCH</b> |                 |             |                 |
| <b>Class</b>               | <b>Subclass</b> | <b>Date</b> | <b>Examiner</b> |
|                            |                 |             |                 |